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# INTERNATIONAL STANDARD

# IEEE Std 1636.1™

## Software Interface for Maintenance Information Collection and Analysis (SIMICA): Exchanging Test Results and Session Information via the eXtensible Markup Language (XML)

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# IEEE Standard for Software Interface for Maintenance Information Collection and Analysis (SIMICA): Exchanging Test Results and Session Information via the eXtensible Markup Language (XML)

Sponsor

**IEEE Standards Coordinating Committee 20 on**
**Test and Diagnosis for Electronic Systems**

Approved 27 September 2018

**IEEE-SA Standards Board**

**Abstract:** Promoting and facilitating interoperability between components of automatic test systems where test results need to be shared is addressed in this standard. The standard thus facilitates the capture of test results data in storage devices and databases, facilitating online and offline analysis. The test results schema becomes a class of information that can be used within the SIMICA family of standards. The exchange format is expressed in both the OWL and XML formats.

**Keywords:** automated test system (ATS), extensible markup language (XML), IEEE 1636.1™, OWL ontology, Software Interface for Maintenance Information Collection and Analysis (SIMICA), test results and session information, XML schema